# MOSFET – Power, Dual N-Channel, SOIC-8 40 V, 5.8 A

#### **Features**

- Designed for use in low voltage, high speed switching applications
- Ultra Low On–Resistance Provides Higher Efficiency and Extends Battery Life
  - $-R_{DS(on)} = 0.027 \Omega$ ,  $V_{GS} = 10 V (Typ)$
  - $-R_{DS(on)} = 0.034 \Omega$ ,  $V_{GS} = 4.5 V (Typ)$
- Miniature SOIC-8 Surface Mount Package Saves Board Space
- Diode is Characterized for Use in Bridge Circuits
- Diode Exhibits High Speed, with Soft Recovery
- NVMD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable\*
- These Devices are Pb-Free and are RoHS Compliant

# **Applications**

- DC-DC Converters
- Computers
- Printers
- Cellular and Cordless Phones
- Disk Drives and Tape Drives

### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	40	V
Gate-to-Source Voltage - Continuous	V <sub>GS</sub>	±20	V
Drain Current (Note 1)  - Continuous @ $T_A = 25^{\circ}C$ - Single Pulse (tp $\leq$ 10 $\mu$ s)	I <sub>D</sub>	5.8 29	Adc Apk
Drain Current (Note 2) - Continuous @ T <sub>A</sub> = 25°C	I <sub>D</sub>	4.6	Adc
Total Power Dissipation @ T <sub>A</sub> = 25°C (Note 1) @ T <sub>A</sub> = 25°C (Note 2)	P <sub>D</sub>	2.0 1.29	W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
	E <sub>AS</sub>	245	mJ
Thermal Resistance  - Junction-to-Ambient (Note 1)  - Junction-to-Ambient (Note 2)	$R_{ heta JA}$	62.5 97	°C/W
Maximum Lead Temperature for Soldering Purposes for 10 Sec	T <sub>L</sub>	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. When surface mounted to an FR4 board using 1" pad size,  $t \le 10 \text{ s}$ 

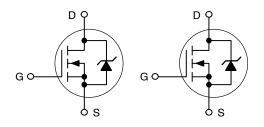


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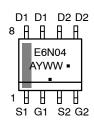
V <sub>DSS</sub>	R <sub>DS(ON)</sub> Typ	I <sub>D</sub> Max	
40 V	27 mΩ @ V <sub>GS</sub> = 10 V	5.8 A	

#### N-Channel



# MARKING DIAGRAM & PIN ASSIGNMENT





E6N04 = Specific Device Code A = Assembly Location

Y = Year WW = Work Week • Pb-Free Package

(Note: Microdot may be in either location)

# **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMD6N04R2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NVMD6N04R2G*	SOIC-8 (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

2.	When surface mounted to an FR4 board using 1" pad size, t = steady state

# **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Chara	acteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage ( $V_{GS}$ = 0 Vdc, $I_D$ = 250 $\mu$ A) Temperature Coefficient (Positive)		V <sub>(BR)DSS</sub> /T <sub>J</sub>	40 -	47 45	- -	Vdc mV/°C
Zero Gate Voltage Drain Current $(V_{DS} = 40 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 25^{\circ}\text{C})$ $(V_{DS} = 40 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 125^{\circ}\text{C})$		I <sub>DSS</sub>	- -	- -	1.0 10	μAdc
Gate-Body Leakage Current (V <sub>GS</sub> = ±20 Vdc, V <sub>DS</sub> = 0 Vdc)		I <sub>GSS</sub>	-	-	± 100	nAdc
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage (V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μAdc) Temperature Coefficient (Negative)		$V_{GS(th)} \ V_{GS(th)}/T_J$	1.0	1.9 4.7	3.0	Vdc mV/°C
Static Drain-to-Source On-State Re $(V_{GS} = 10 \text{ Vdc}, I_D = 5.8 \text{ Adc})$ $(V_{GS} = 4.5 \text{ Vdc}, I_D = 3.9 \text{ Adc})$	sistance	R <sub>DS(on)</sub>	- -	0.027 0.034	0.034 0.043	Ω
Forward Transconductance (V <sub>DS</sub> = 10 Vdc, I <sub>D</sub> = 5.8 Adc)		9FS	_	8.12	-	Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance		C <sub>iss</sub>	-	723	900	pF
Output Capacitance	(V <sub>DS</sub> = 32 Vdc, V <sub>GS</sub> = 0 Vdc, f = 1.0 MHz)	C <sub>oss</sub>	-	156	225	
Reverse Transfer Capacitance		C <sub>rss</sub>	1	53	75	1
SWITCHING CHARACTERISTICS (N	otes 3 & 4)					•
Turn-On Delay Time		t <sub>d(on)</sub>	-	10	18	ns
Rise Time	$(V_{DD} = 20 \text{ Vdc}, I_D = 5.8 \text{ A}, V_{GS} = 10 \text{ V},$	t <sub>r</sub>	-	20	35	
Turn-Off Delay Time	$R_{G} = 10 \text{ V},$ $R_{G} = 6 \Omega)$	t <sub>d(off)</sub>	-	45	70	
Fall Time		t <sub>f</sub>	-	40	65	
Turn-On Delay Time		t <sub>d(on)</sub>	-	15	-	ns
Rise Time	$(V_{DD} = 20 \text{ Vdc}, I_D = 5.8 \text{ A},$	t <sub>r</sub>	-	55	-	
Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V},$ $R_G = 6 \Omega)$	t <sub>d(off)</sub>	-	30	-	
Fall Time		t <sub>f</sub>	-	35	-	
Gate Charge	(V <sub>DS</sub> = 20 Vdc,	Q <sub>T</sub>	-	20	30	nC
	$V_{GS} = 10 \text{ Vdc},$	Q <sub>gs</sub>	_	2.5	-	
	I <sub>D</sub> = 5.8 A)	Q <sub>gd</sub>	-	5.5	_	
BODY-DRAIN DIODE RATINGS (Not	e 3)	+			1	
Diode Forward On-Voltage	$(I_S = 1.7 \text{ Adc}, V_{GS} = 0 \text{ V})$ $(I_S = 1.7 \text{ Adc}, V_{GS} = 0 \text{ V}, T_J = 150^{\circ}\text{C})$	V <sub>SD</sub>	-	0.76 0.56	1.1 -	Vdc
Reverse Recovery Time		t <sub>rr</sub>	-	23	_	ns
	$(I_S = 1.7 \text{ A}, V_{GS} = 0 \text{ V}, \\ dI_S/dt = 100 \text{ A/}\mu\text{s})$	t <sub>a</sub>	ı	16	_	
		t <sub>b</sub>	1	7	-	
Reverse Recovery Stored Charge (I <sub>S</sub> = 1.7 A, dI <sub>S</sub> /dt = 100 A/μs, V <sub>GS</sub> = 0 V)		Q <sub>RR</sub>	-	20	_	nC

<sup>3.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperature.

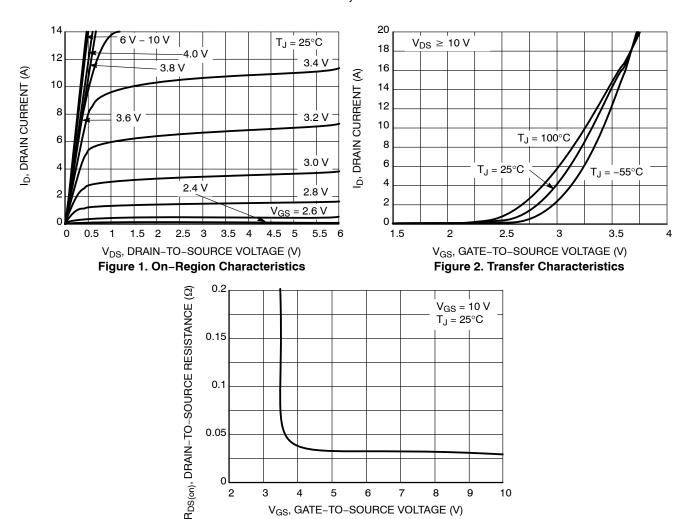


Figure 3. On-Resistance vs. Gate-to-Source Voltage

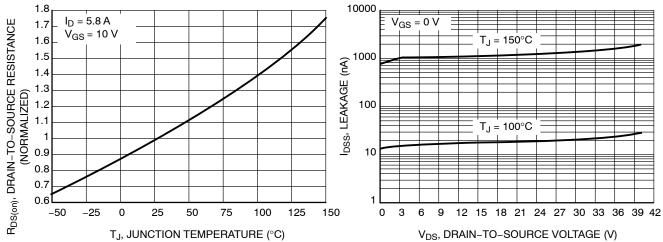


Figure 4. On Resistance Variation with Temperature

Figure 5. Drain-to-Source Leakage Current vs. Voltage

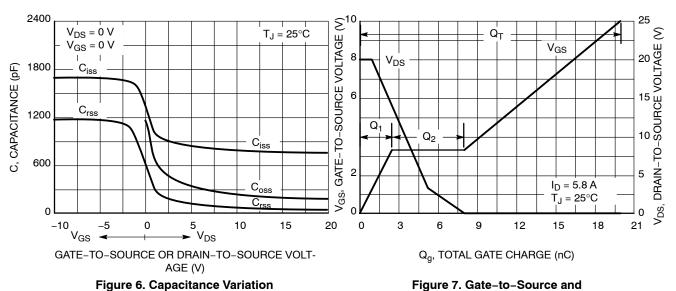


Figure 6. Capacitance Variation

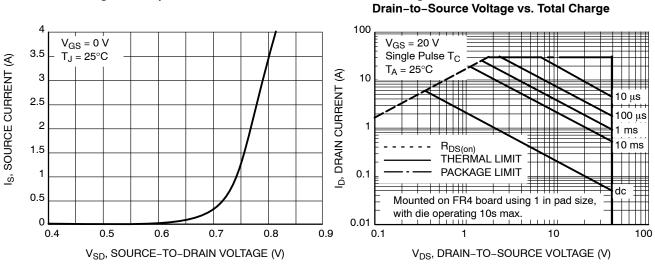
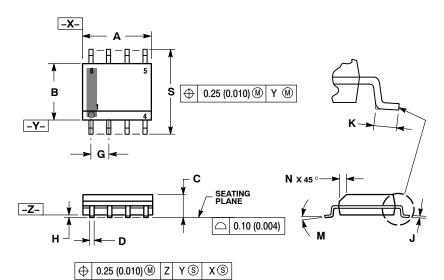


Figure 8. Diode Forward Voltage vs. Current

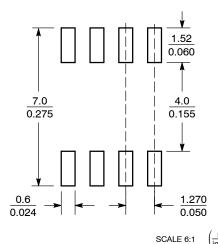
Figure 9. Maximum Rated Forward Biased Safe Operating Area

#### PACKAGE DIMENSIONS

#### SOIC-8 NB CASE 751-07 **ISSUE AK**



#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14 5M 1982
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. 751–01 THRU 751–06 ARE OBSOLETE. NEW
- STANDARD IS 751-07.

	MILLIN	IETERS	INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27	7 BSC	0.050 BSC	
Н	0.10	0.25	0.004 0.010	
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010 0.020	
S	5.80	6.20	0.228	0.244

#### STYLE 11:

- SOURCE 1 PIN 1. GATE 1

  - SOURCE 2 3. 4.
  - GATE 2 DRAIN 2 5.
  - 6. DRAIN 2
  - DRAIN 1 DRAIN 1

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